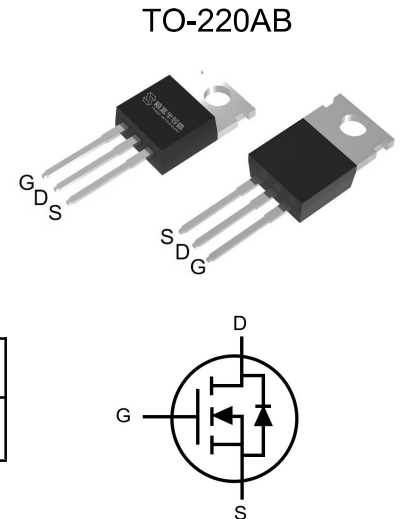


Features

- Enhancement mode
- Very low on-resistance
- VitoMOS® II Technology
- 100% Avalanche Tested, Rg 100% Tested
- Optimized Qg, Qgd, and Qgd/Qgs ratio to minimize switching losses



Part ID	Package Type	Marking	Packing
VS1696GTH	TO-220AB	1696GTH	50pcs/Tube



Maximum ratings, at T_A =25°C, unless otherwise specified

Symbol	Parameter		Rating	Unit
V(BR)DSS	Drain-Source breakdown voltage		100	V
VGS	Gate-Source voltage		±20	V
IS	Diode continuous forward current (Silicon limited)	T _C = 25°C	278	A
ID	Continuous drain current @VGS=10V (Silicon limited)	T _C = 25°C	278	A
ID	Continuous drain current @VGS=10V (Silicon limited)	T _C = 100°C	197	A
ID	Continuous drain current @VGS=10V (Wire bond limited)	T _C = 25°C	180	A
IDM	Pulse drain current tested ①	T _C = 25°C	1112	A
IDSM	Continuous drain current @VGS=10V	T _A = 25°C	20	A
		T _A = 70°C	16	A
EAS	Avalanche energy, single pulsed ②		1681	mJ
PD	Maximum power dissipation ③	T _C = 25°C	417	W
PDSM	Maximum power dissipation ④	T _A = 25°C	2.1	W
TSTG,TJ	Storage and Junction Temperature Range		-55 to 175	°C

Thermal Characteristics

Symbol	Parameter	Typical	Max	Unit
RθJC	Thermal Resistance, Junction-to-Case ⑤	0.3	0.36	°C/W
RθJA	Thermal Resistance, Junction-to-Ambient ⑥	50	60	°C/W

Electrical Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max	Unit
Static Electrical Characteristics @ T _j =25°C (unless otherwise stated)						
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	100	—	—	V
I _{DSS}	Zero Gate Voltage Drain Current(T _j =25°C)	V _{DS} =100V,V _{GS} =0V	—	—	1	μA
	Zero Gate Voltage Drain Current(T _j =125°C)⑦	V _{DS} =100V,V _{GS} =0V	—	—	100	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V,V _{DS} =0V	—	—	±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} ,I _D =250μA	2.4	2.9	3.4	V
R _{DS(on)}	Drain-Source On-State Resistance ⑧	V _{GS} =10V, I _D =40A	--	2.2	2.9	mΩ
		T _j =100°C ⑦	—	3	—	mΩ
Dynamic Electrical Characteristics @ T _j = 25°C (unless otherwise stated)						
C _{iss}	Input Capacitance ⑦	V _{DS} =50V,V _{GS} =0V, f=1MHz	—	13510	—	pF
C _{oss}	Output Capacitance ⑦		—	2025	—	pF
C _{rss}	Reverse Transfer Capacitance ⑦		—	55	—	pF
R _g	Gate Resistance	f=1MHz	—	1	—	Ω
Q _g	Total Gate Charge ⑦	V _{DS} =50V,I _D =40A, V _{GS} =10V	—	177	—	nC
Q _{gs}	Gate-Source Charge ⑦		—	50	—	nC
Q _{gd}	Gate-Drain Charge ⑦		—	47	—	nC
Switching Characteristics ⑦						
T _{d(on)}	Turn-on Delay Time	V _{DD} =50V, I _D =40A, R _G =3Ω, V _{GS} =10V	—	34	—	ns
T _r	Turn-on Rise Time		—	67	—	ns
T _{d(off)}	Turn-Off Delay Time		—	85	—	ns
T _f	Turn-Off Fall Time		—	69	—	ns
Source- Drain Diode Characteristics@ T _j = 25°C (unless otherwise stated)						
V _{SD}	Forward on voltage	I _{SD} =40A,V _{GS} =0V	—	0.8	1.2	V
T _{rr}	Reverse Recovery Time ⑦	I _{sd} =40A, V _{GS} =0V di/dt=100A/μs	—	134	—	ns
Q _{rr}	Reverse Recovery Charge ⑦		—	223	—	nC

NOTE:

- ① Single pulse; pulse width ≤ 100μs.
- ② EAS of 1681mJ is based on starting T_j = 25°C, L = 0.5mH, R_G = 25Ω, I_{AS} = 82A, V_{GS} = 10V; 100% FT tested at L = 0.5mH, I_{AS} = 45A.
- ③ The power dissipation P_d is based on T_j(max), using junction-to-case thermal resistance RθJC.
- ④ The power dissipation P_{dsm} is based on T_j(max), using junction-to-ambient thermal resistance RθJA.
- ⑤ Thermal resistance from junction to soldering point (on the exposed drain pad). These tests are performed on a cool plate.
- ⑥ These tests are performed with the device mounted on 1 in2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C.
- ⑦ Guaranteed by design, not subject to production testing.
- ⑧ Pulse width ≤ 380μs; duty cycles ≤ 2%.

Typical Characteristics

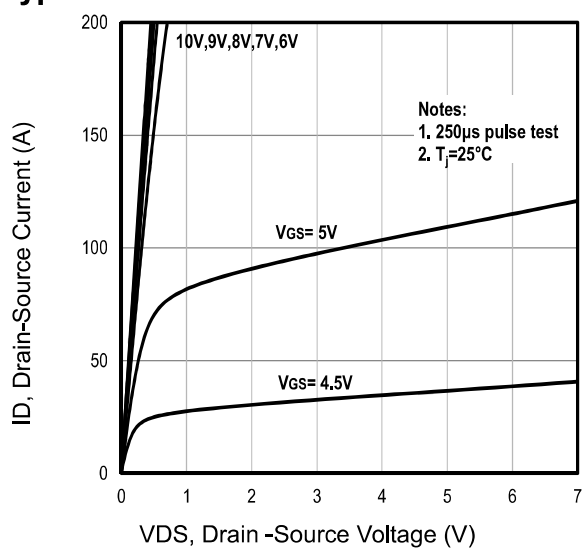


Fig1. Typical Output Characteristics

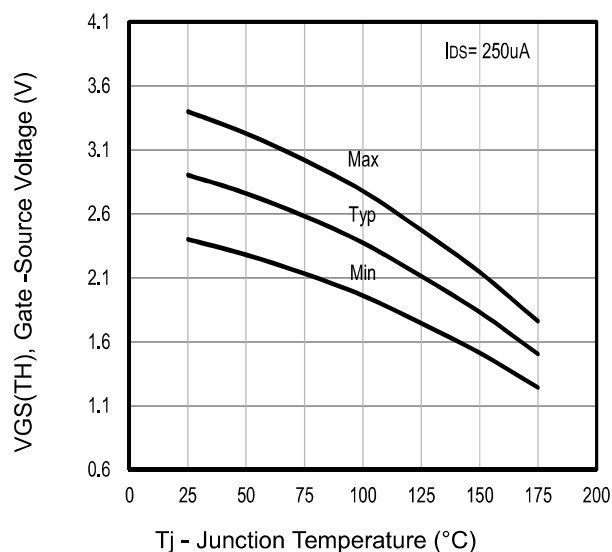


Fig2. Typical $V_{GS(TH)}$ Gate-Source Voltage Vs. T_J

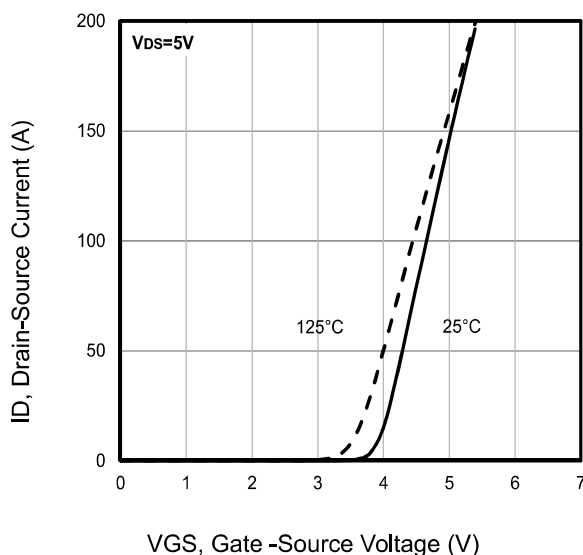


Fig3. Typical Transfer Characteristics

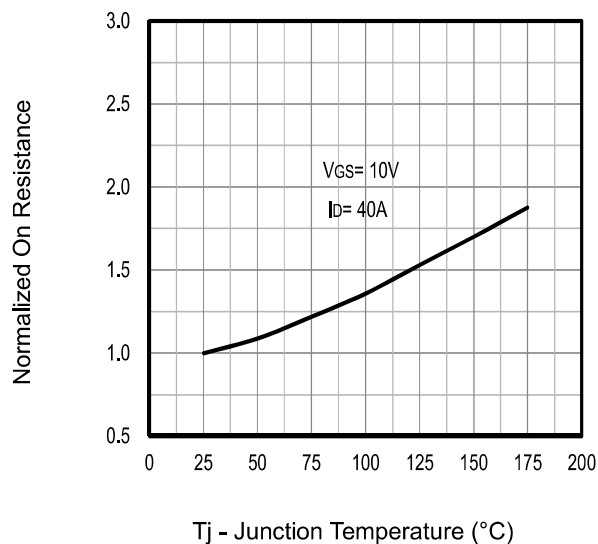


Fig4. Typical Normalized On-Resistance Vs. T_J

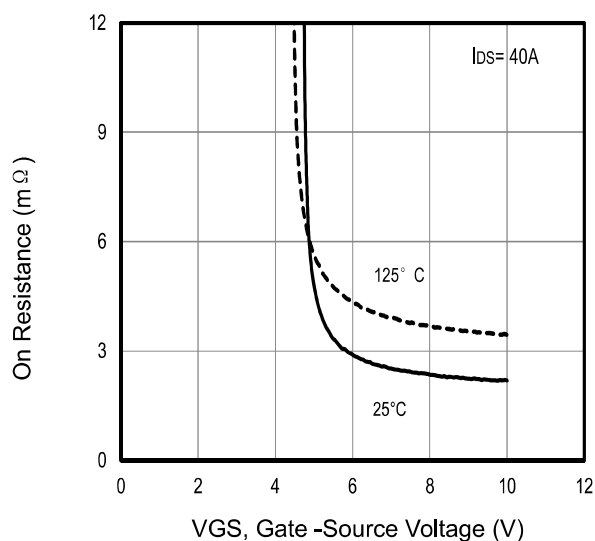


Fig5. Typical On Resistance Vs Gate-Source Voltage

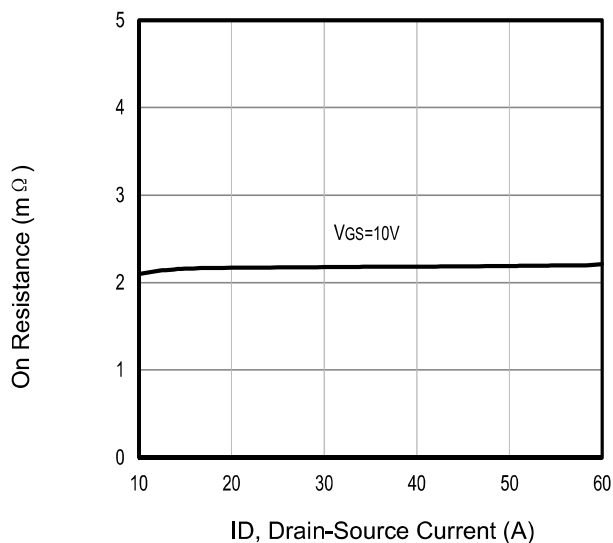


Fig6. Typical On Resistance Vs Drain Current

Typical Characteristics

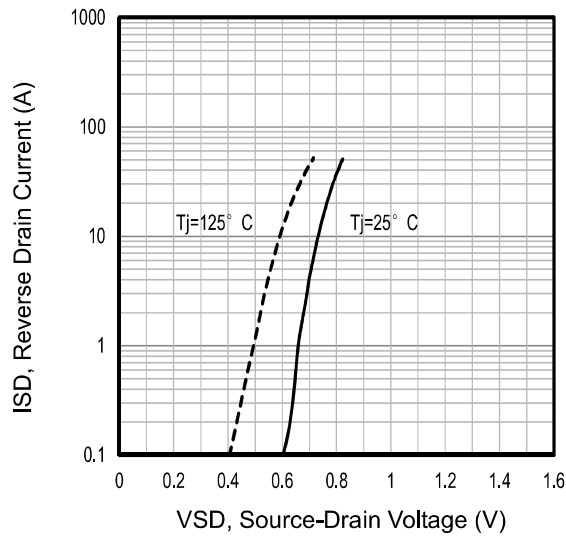


Fig7. Typical Source-Drain Diode Forward Voltage

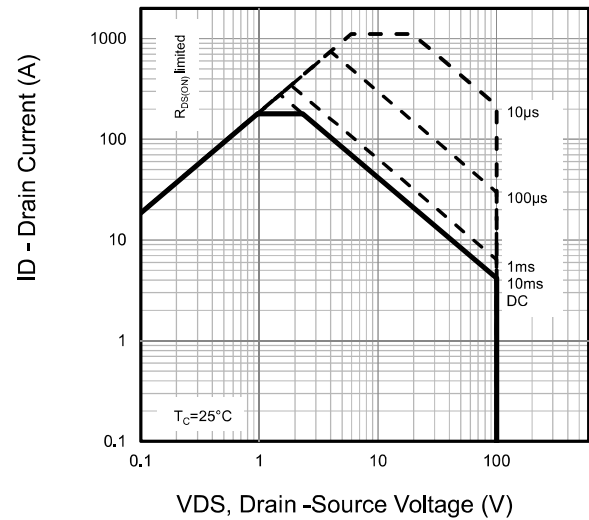


Fig8. Maximum Safe Operating Area

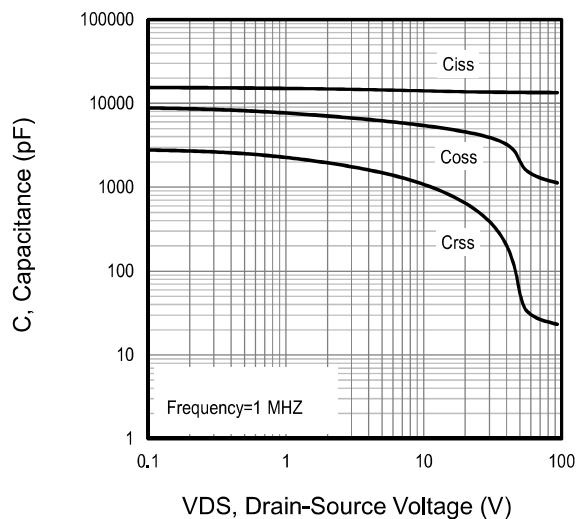


Fig9. Typical Capacitance Vs. Drain-Source Voltage

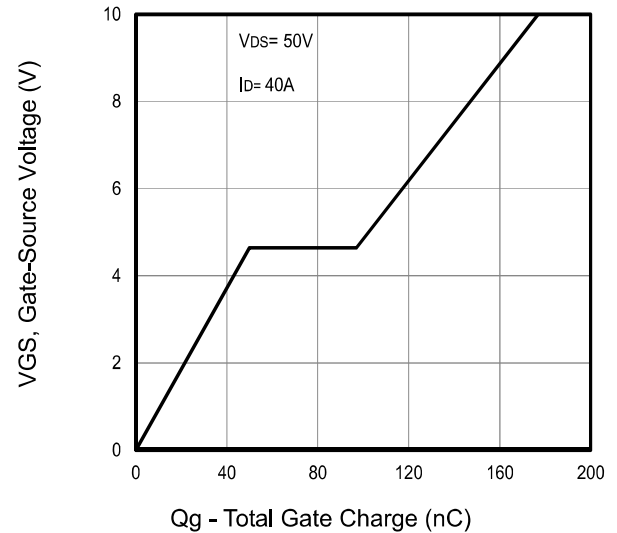


Fig10. Typical Gate Charge Vs. Gate-Source Voltage

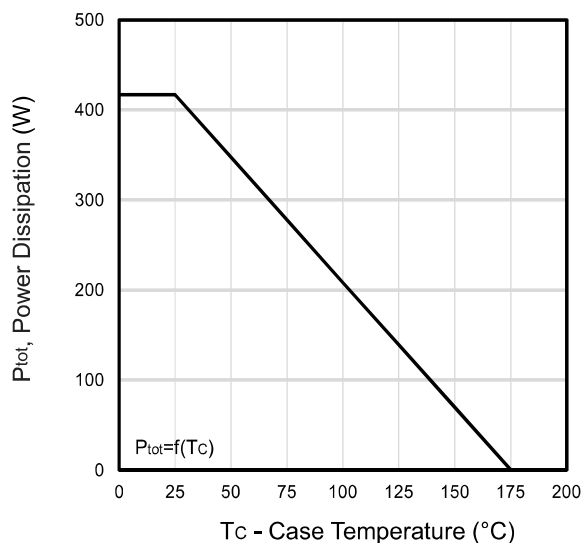


Fig11. Power Dissipation Vs. Case Temperature

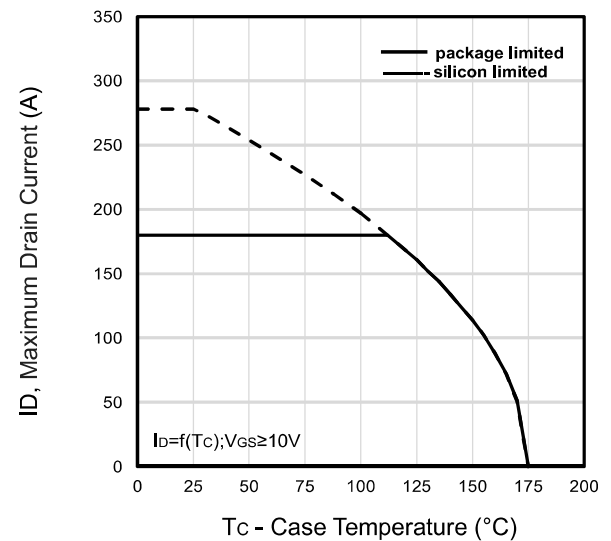


Fig12. Maximum Drain Current Vs. Case Temperature

Typical Characteristics

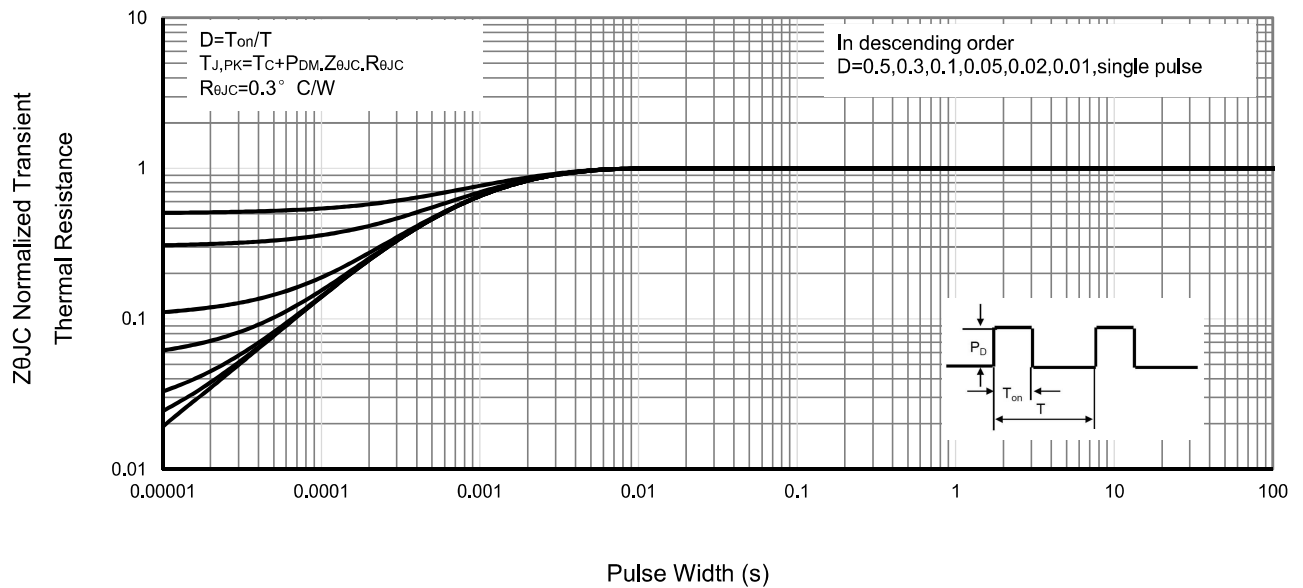


Fig13 . Normalized Maximum Transient Thermal Impedance

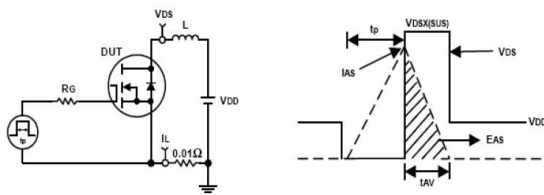


Fig14. Unclamped Inductive Test Circuit and waveforms

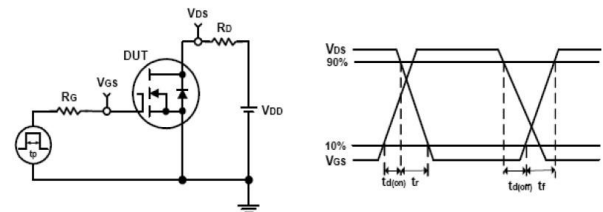
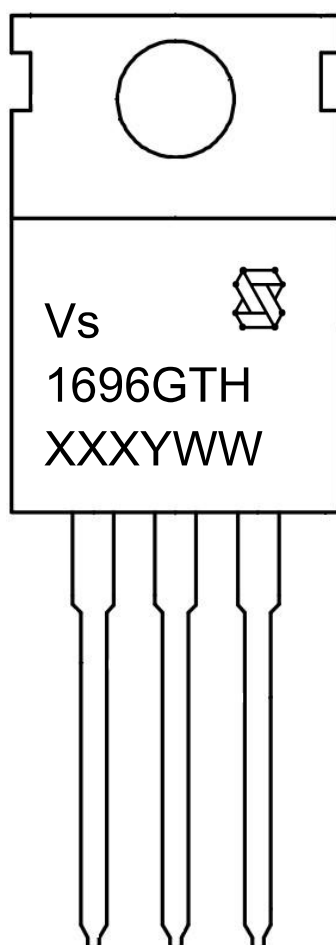


Fig15. Switching Time Test Circuit and waveforms

Marking Information



1st line: Vergiga Code (Vs), Vergiga Logo

2nd line: Part Number (1696GTH)

3rd line: Date code (XXXYWW)

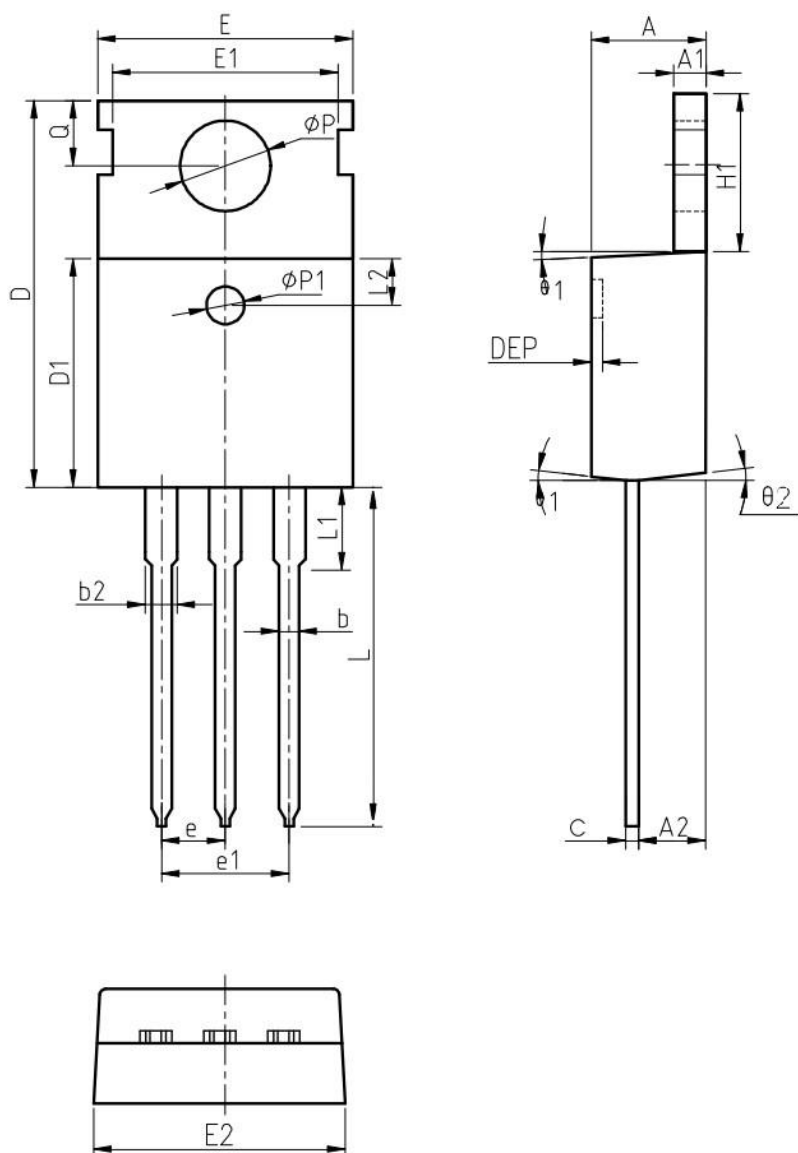
XXX: Wafer Lot Number Code , code changed with Lot Number

Y: Year Code , refer to table below

WW: Week Code (01 to 53)

Code	C	D	E	F	G	H	J	K	L	M	N	P	Q	R	S	T
Year	2015	2016	2017	2018	2019	2020	2021	2022	2023	2024	2025	2026	2027	2028	2029	2030

TO-220AB Package Outline Data



Symbol	Dimensions (unit: mm)		
	Min	Typ	Max
A	4.30	4.52	4.70
A1	1.15	1.30	1.40
A2	2.20	2.40	2.60
b	0.70	0.80	1.00
b2	1.17	1.32	1.50
c	0.45	0.50	0.61
D	15.30	15.65	15.90
D1	9.00	9.20	9.40
DEP	0.05	0.10	0.25
E	9.66	9.90	10.28
E1	-	8.70	-
E2	9.80	10.00	10.20
$\phi P1$	1.40	1.50	1.60
e	2.54 BSC		
e1	5.08 BSC		
H1	6.40	6.50	6.80
L	12.70	-	14.27
L1	-	-	3.95
L2	2.40	2.50	2.60
ϕP	3.53	3.60	3.70
Q	2.70	2.80	2.90
$\theta 1$	5 °	7 °	9 °
$\theta 2$	1 °	3 °	5 °

Notes:

1. Refer to JEDEC TO-220 variation AB
2. Dimension "D" and "E" do NOT include mold flash. Mold flash shall not exceed 0.127mm per side.

Customer Service

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